

DATA SHEET							Date	12-Aug-03														
Model	CQS48018-50						Temp.	25 degreeC														
Test	EMI Line conduction & Radiated emission						Humid.	45 %RH														
							Tested by	R.Sakai														
LINE CONDUCTION																						
Model Name : CQS48018-50				Temp. : 25																		
Model No. :				Humi. : 45																		
Serial No. :				Date : 2003/8/12 21:21																		
Points : 2				Test Equip. : R3132,ESPC																		
Detector : PEAK/QP/Ave.				Comment : R.Sakai																		
Line Mode : VA/VB				Load 100%(+1.8V 50A)																		
Power Supply : DC 48V																						
Limit1: [EN 55022] Class A(QP)																						
Limit2: [EN 55022] Class A(Ave.)																						
							Limit1(QP)		Limit2(Ave.)		VA(PEAK)		VB(PEAK)		VA(QP)		VA(Ave.)		VB(QP)		VB(Ave.)	
							DC 48V															
							Load 100%(+1.8V 50A)															
Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]												
22.3338	38.4	38.7	10.3	48.7	49	VA	60	73	11.3	24												
0.4057	44.6	44.3	9.9	54.5	54.2	VB	66	79	11.5	24.8												

COSEL

○ Testing circuitry

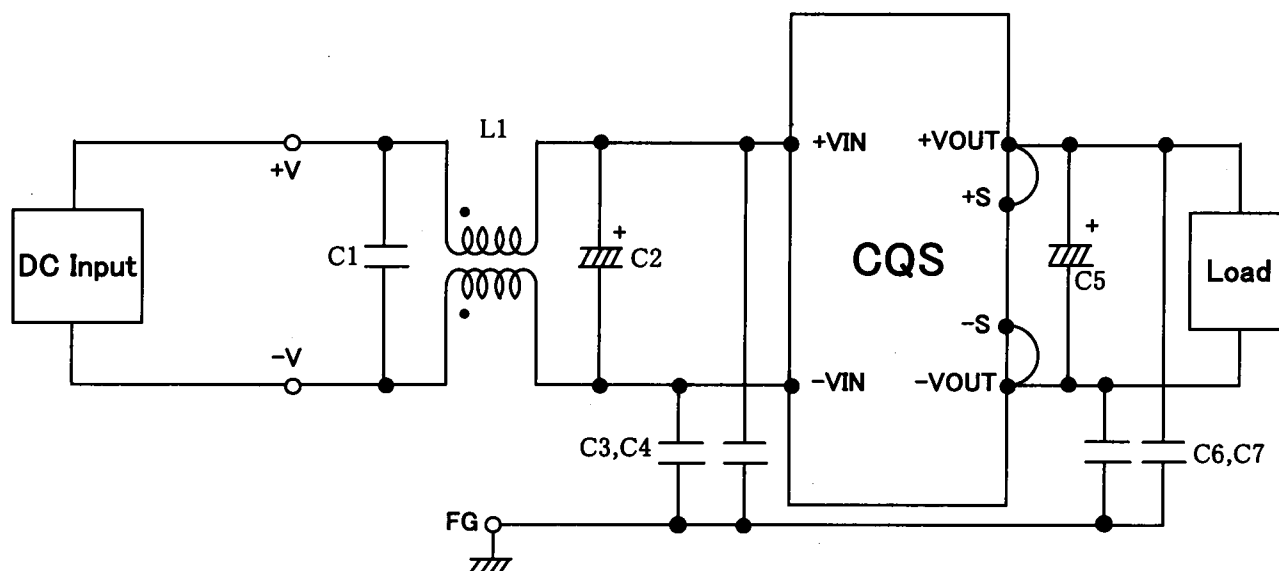


Fig.1 Testing circuitry

- L1 : 1mH SC-05-10J (TOKIN)
 C1 : 2.2 μ F MDS22A225K (NITSUKO)
 C2 : 100V 33 μ F PWseries (nichicon)
 C3,4 : 630V 0.068 μ F MDS22J683K (NITSUKO)
 C5 : 10V 10 μ F PMseries (nichicon)
 C6,7 : 630V 0.033 μ F MDS22J333K (NITSUKO)

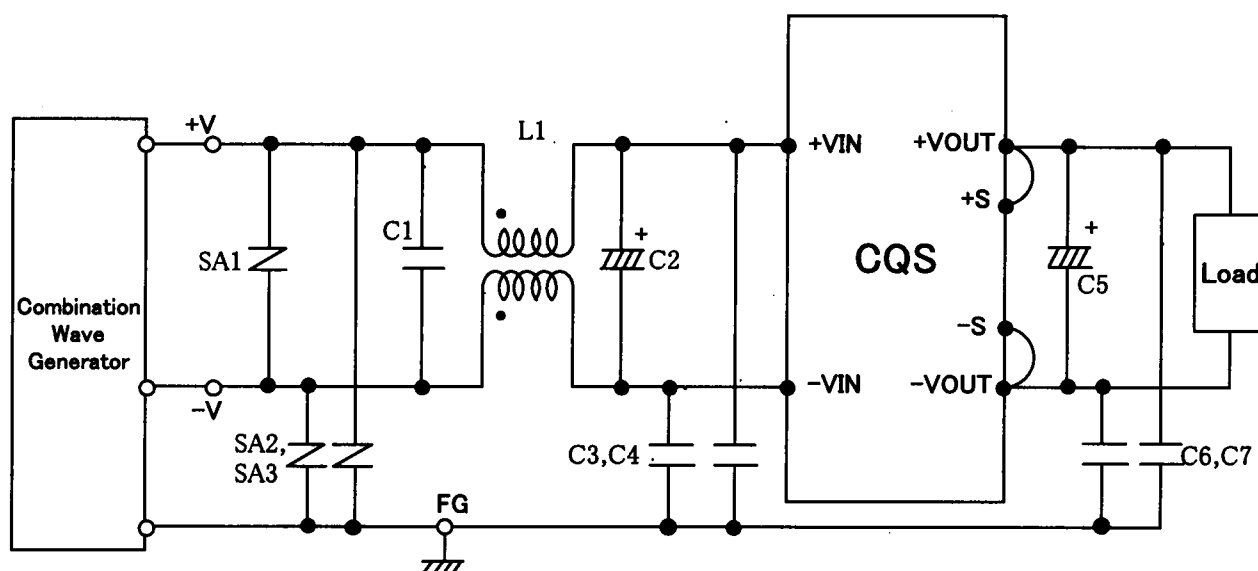


Fig.2 Surge immunity Testing circuitry

- L1 : 1mH SC-05-10J (TOKIN)
 C1 : 2.2 μ F MDS22A225K (NITSUKO)
 C2 : 100V 33 μ F PWseries (nichicon)
 C3,4 : 630V 0.068 μ F MDS22J683K (NITSUKO)
 C5 : 10V 10 μ F PMseries (nichicon)
 C6,7 : 630V 0.033 μ F MDS22J333K (NITSUKO)
 SA1~3: ERZV10D101 (100V)